


<b>Search Notes</b>  	<b>Application/Control No.</b>  10629020	<b>Applicant(s)/Patent Under Reexamination</b>  EZELL, R. WILLIAM
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	316	12/15/2006	Siu M. Lee
327	553	12/15/2006	Siu M. Lee
330	303	12/15/2006	Siu M. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
US-PGPUB	12/15/2006	Siu M. Lee
USPAT	12/15/2006	Siu M. Lee
USOCR	12/15/2006	Siu M. Lee
EPO	12/15/2006	Siu M. Lee
JPO	12/15/2006	Siu M. Lee
DERWENT	12/15/2006	Siu M. Lee
IBM_TDB	12/15/2006	Siu M. Lee
Discussed the application with Chieh Fan	12/15/2006	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner